

# Design Rules for NMOS



- Design Rules
- Stick Diagrams
- Layout Diagram
- Examples

# Design Rules: Introduction

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- ❑ Design rules are a set of geometrical specifications that **dictate the design** of the layout
- ❑ **Layout is top view of a chip.**
- ❑ Design process are aided by stick diagram and layout
- ❑ Stick diagram gives the placement of different components and their connection details
- ❑ But the dimensions of devices are not mentioned
- ❑ Circuit design with all dimensions is Layout

# Design Rules: Introduction

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- ❑ Fabrication process needs different masks, these masks are prepared from layout
- ❑ Layout is an Interface between circuit designer and fabrication engineer
- ❑ Layout is made using a set of design rules.
- ❑ Design rules allow translation of circuit (usually in stick diagram or symbolic form) into actual geometry in silicon wafer
- ❑ These rules usually specify the minimum allowable line widths for physical objects on-chip
- ❑ Example: metal, polysilicon, interconnects, diffusion areas, minimum feature dimensions, and minimum allowable separations between two such features.

# NEED FOR DESIGN RULES







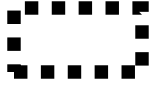
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- ❑ Better area efficiency
- ❑ Better yield
- ❑ Better reliability
- ❑ Increase the probability of fabricating a successful product on Si wafer

If design rules are not followed:

- Functional or non-functional circuit.
- Design consuming larger Si area.
- The device can fail during or after simulation.

# Colour Codes :

Layer	Color	Representation
N+ Active	Green	
P+ Active	Yellow/Brown	
PolySi	Red	
Metal 1	Blue	
Metal 2	Magenta	
Contact	Black	<b>X</b>
Buried contact	Brown	<b>X</b>
Via	Black	<b>X</b>
Implant	Dotted yellow	
N-Well	Dotted Green/Black	

# Stick Diagrams :

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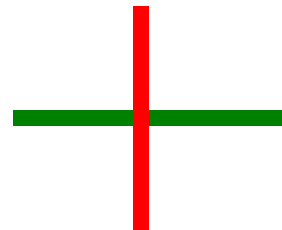
- ❑ A stick diagram is a symbolic representation of a layout.
- ❑ In stick diagram, each conductive layer is represented by a line of distinct color.
- ❑ Width of line is not important, as stick diagrams just give only wiring and routing information.
- ❑ Does show all components/vias, relative placement.
- ❑ Does not show exact placement, transistor sizes, wire lengths, wire widths, tub boundaries.

# Stick Diagrams: Basic Rules

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- Poly crosses diffusion forms transistor
- Red (poly) over Green(Active), gives a FET.

L:W



nFET/  
nMOS

- Aspect Ratio

L:W



pFET/pMOS

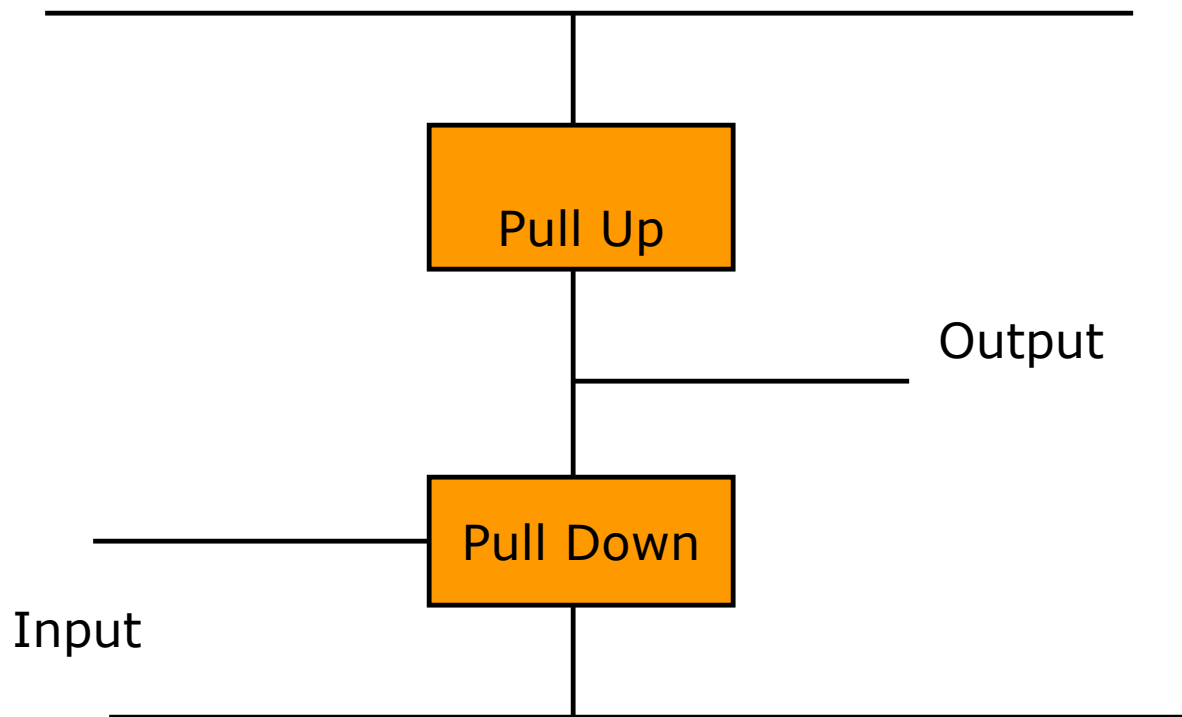
# Inverter Using MOSFET

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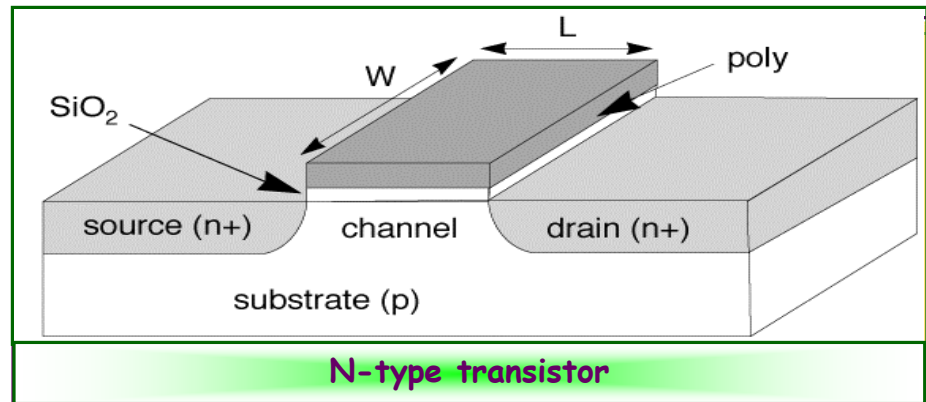
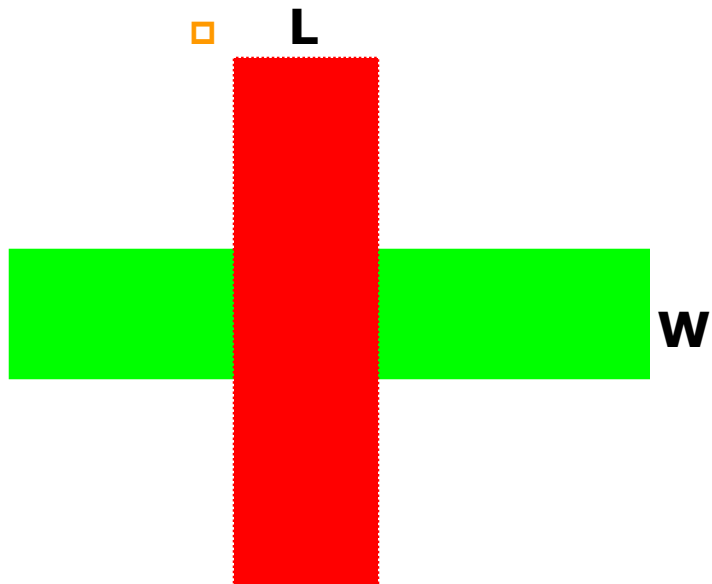
- ❑ Enhancement-Mode MOSFETs act as switches.
- ❑ They are switched OFF, when the input to gate is low.
- ❑ So, they can be used to pull the output down.
- ❑ Now, for pull-up, we can use a resistor.
- ❑ But resistors consume larger area.
- ❑ Another alternative is using MOSFET as pull-up.
- ❑ PU's can be NMOS or PMOS.

# Inverter Using MOSFET

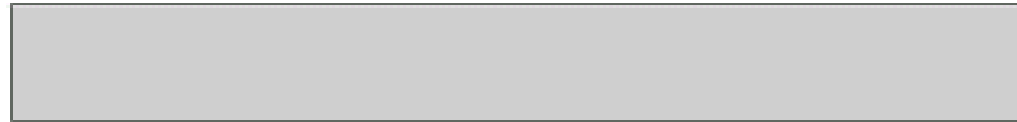
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# MOSFET



**A silicon wafer**



# Types of Layout Design Rules

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- Industry Standard: Micron Rule
- $\lambda$  Based Design Rules

# Types of Design Rules (Contd...)

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## □ Industry Standard: Micron Rule

- All device dimensions are expressed in terms of absolute dimension( $\mu\text{m}/\text{nm}$ )
- These rules will not support proportional scaling

# Types of Design Rules (Contd...)

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## □ $\lambda$ Based Design Rules :

- Developed by Mead and Conway.
- All device dimensions are expressed in terms of a scalable parameter  $\lambda$ .
- $\lambda = L/2$ ;  $L$  = The minimum feature size of transistor
- $L = 2\lambda$
- These rules support proportional scaling.
- They should be applied carefully in sub-micron CMOS process.

# Design Rules

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- Minimum **length or width** of a feature on a layer is  **$2\lambda$** 
  - To allow for shape contraction
- Minimum **separation** of features on a layer is  **$2\lambda$** 
  - To ensure adequate continuity of the intervening materials.

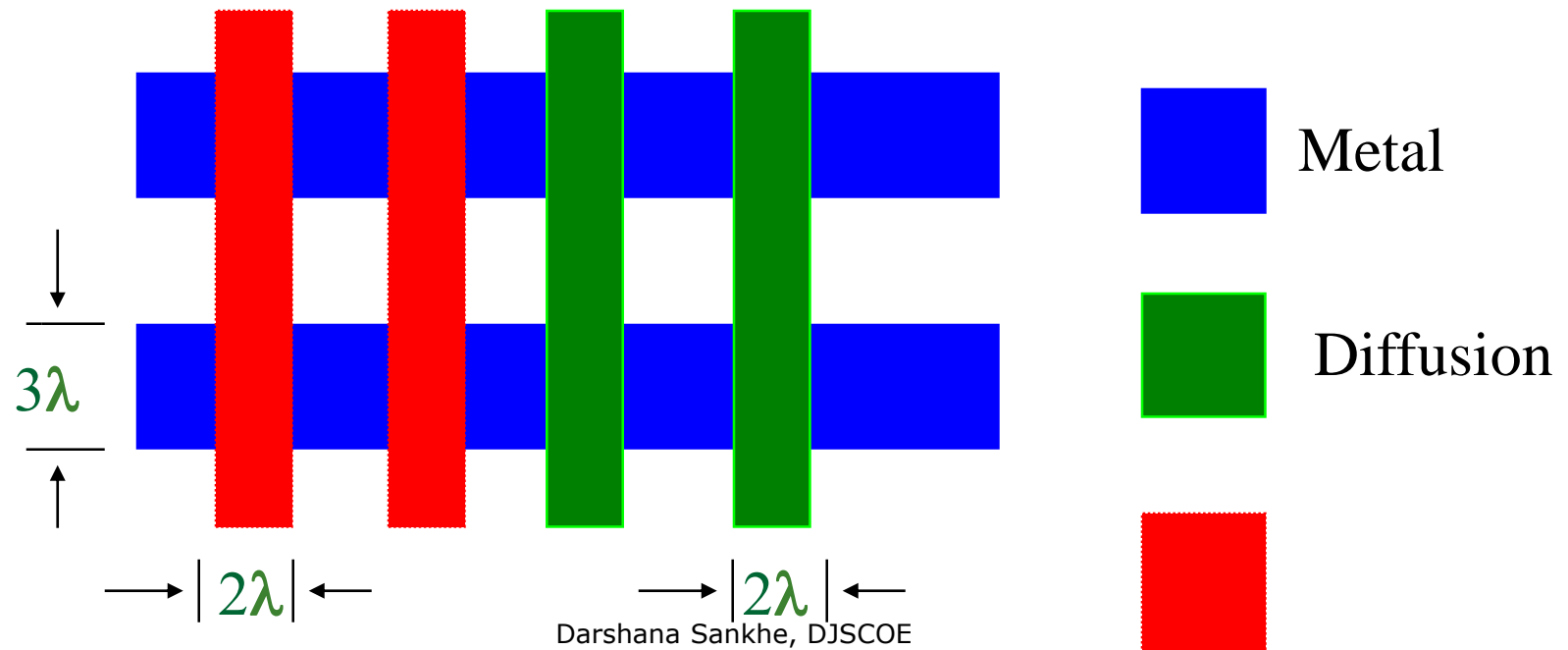
# Design Rules :

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- Two Features on different mask layers can be misaligned by a maximum of  $2\lambda$  on the wafer.
- If the overlap of these two different mask layers can be catastrophic to the design, they must be separated by at least  $2\lambda$
- If the overlap is just undesirable, they must be separated by at least  $\lambda$

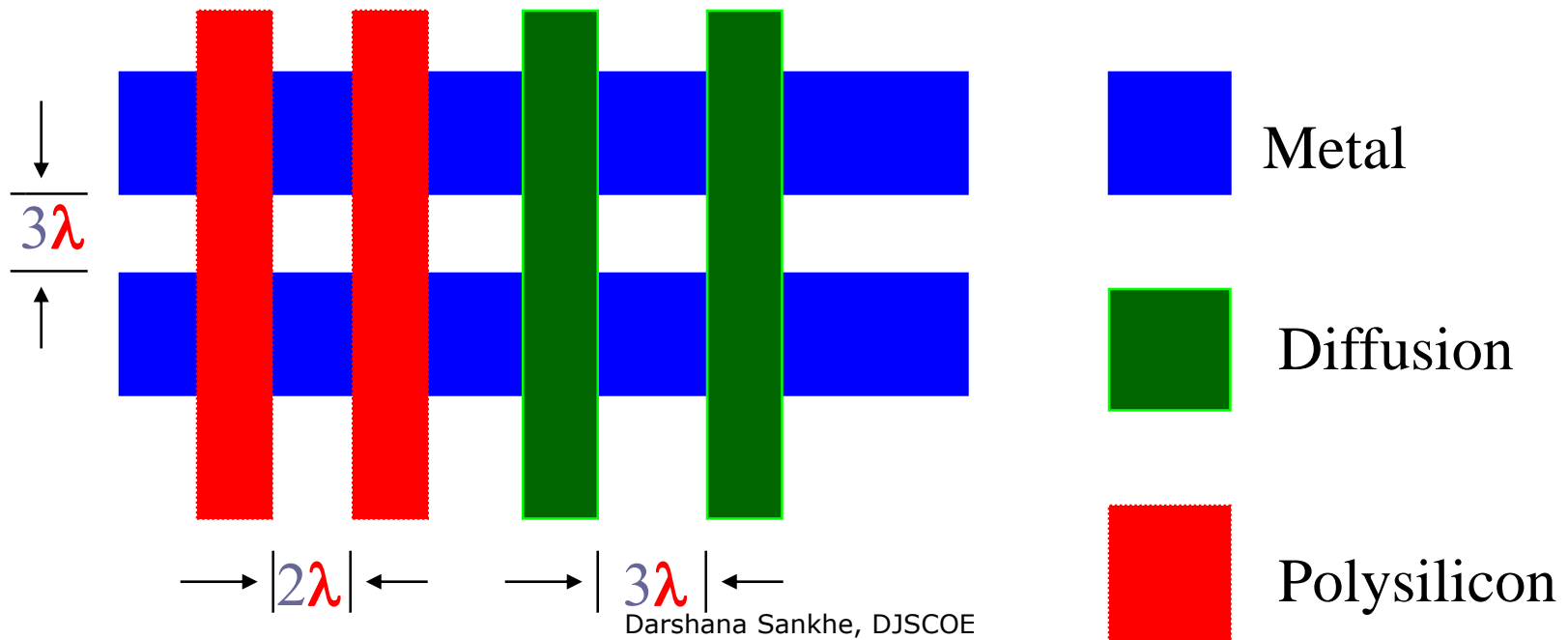
# Design Rules: NMOS

- Minimum width of PolySi and diffusion line  $2\lambda$
- Minimum width of Metal line  $3\lambda$  as metal lines run over a more uneven surface than other conducting layers to ensure their continuity



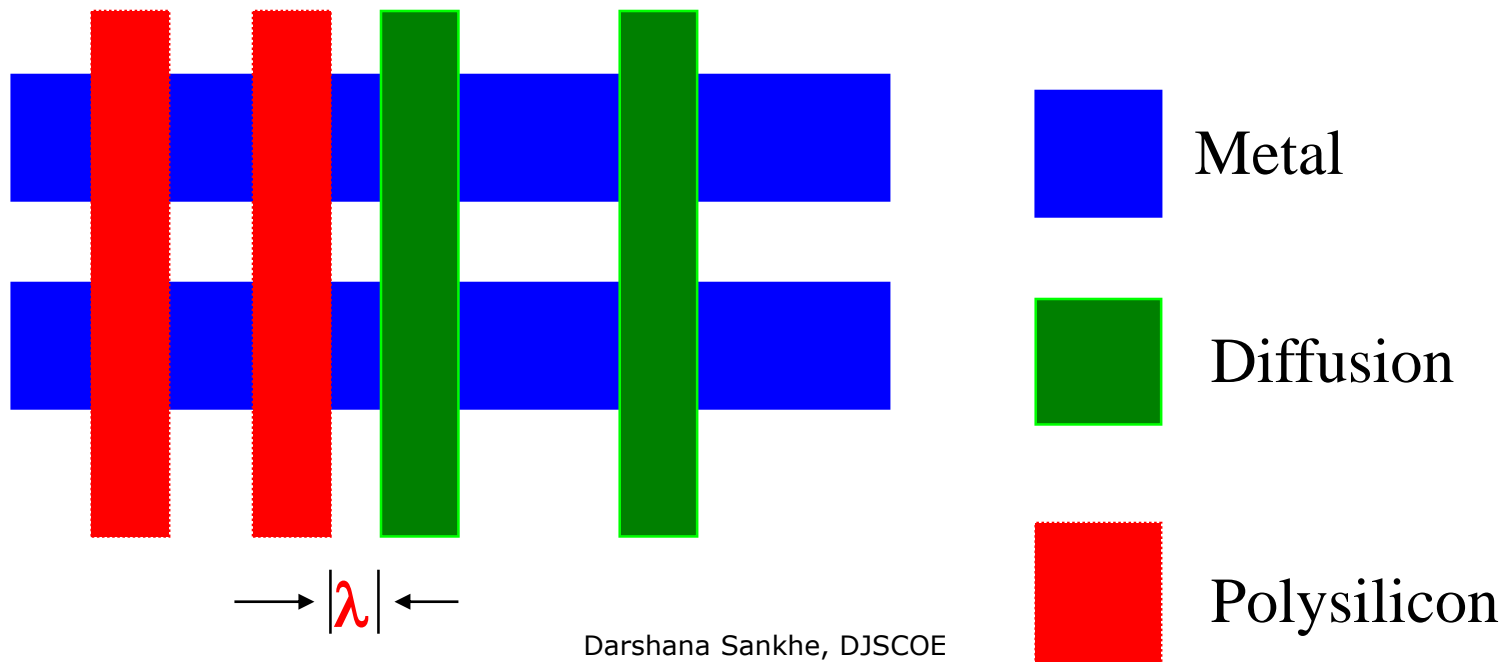
# Design Rules: NMOS

- PolySi – PolySi spacing  $2\lambda$
- Metal - Metal spacing  $3\lambda$
- Diffusion – Diffusion spacing  $3\lambda$  To avoid the possibility of their associated regions overlapping and conducting current



# Design Rules: NMOS

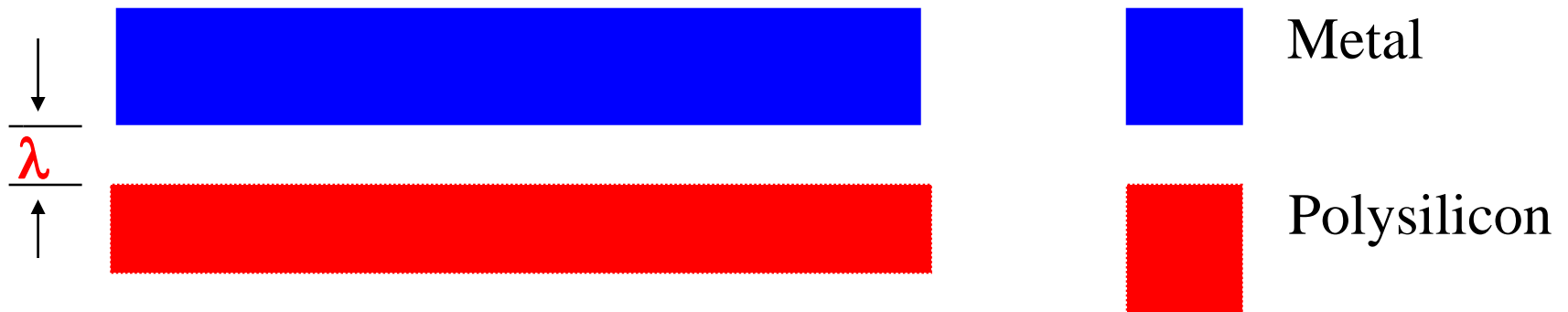
- **Diffusion – PolySi spacing  $\lambda$  To prevent the lines overlapping to form unwanted capacitor.**
- **Metal lines can pass over both diffusion and polySi without electrical effect. Where no separation is specified, metal lines can overlap or cross.**



# Design Rules: NMOS

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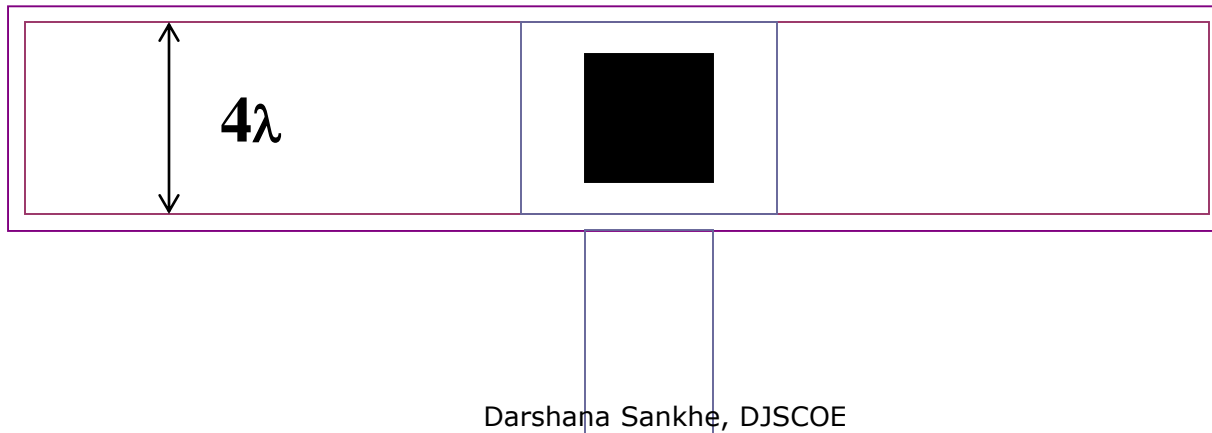
- ❑ Metal lines can pass over both diffusion and polySi without electrical effect
- ❑ It is recommended practice to **leave  $\lambda$**  between a **metal edge** and a **polySi** or diffusion line to which it is not electrically connected



# Contact Cut :

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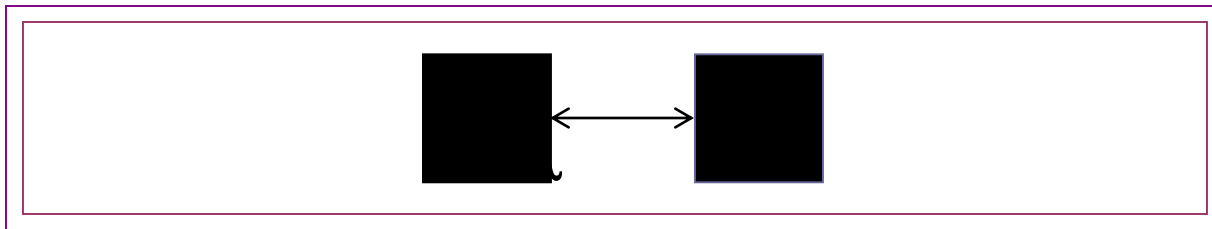
- Metal connects to polySi/diffusion by contact cut.
- Contact area:  $2\lambda * 2\lambda$
- Metal and polySi or diffusion must overlap this contact area by  $\lambda$  so that the two desired conductors encompass the contact area despite any misalignment between conducting layers and the contact hole



# Contact Cut

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- **Contact cut – contact cut:  $2\lambda$  apart**
- **Why? To prevent holes from merging.**



# Design Rules: NMOS

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- Minimum diff width  $2\lambda$
- Minimum poly width  $2\lambda$
- Minimum metal width  $3\lambda$
- poly-poly spacing  $2\lambda$
- diff-diff spacing  $3\lambda$   
(depletion regions tend to spread outward)
- metal-metal spacing  $3\lambda$
- diff-poly spacing  $\lambda$

# Design Rules: NMOS

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- ❑ Poly gate extend beyond diff by  $2\lambda$
- ❑ Diff extend beyond poly by  $2\lambda$
- ❑ Contact size  $2\lambda * 2\lambda$
- ❑ Contact diff/poly/metal overlap  $1\lambda$
- ❑ Contact to contact spacing  $2\lambda$
- ❑ Contact to poly/diff spacing  $2\lambda$
- ❑ Buried contact to active device spacing  $2\lambda$
- ❑ Buried contact overlap in diff direction  $2\lambda$
- ❑ Buried contact overlap in poly direction  $1\lambda$
- ❑ Implant gate overlap  $2\lambda$

# Aspect Ratio For Pull-up and Pull-down

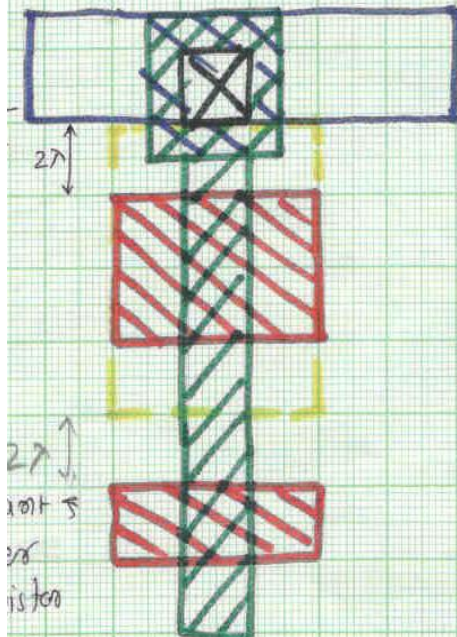
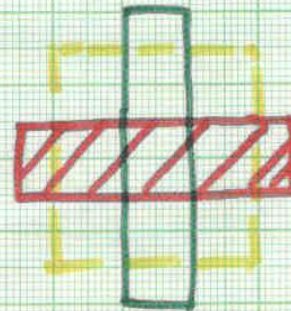
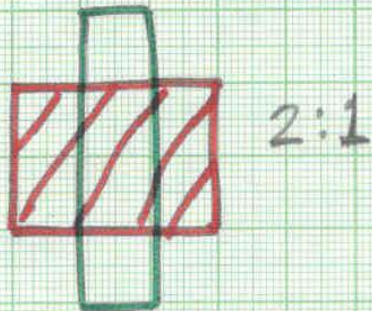
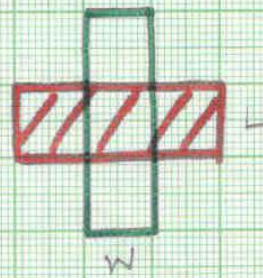
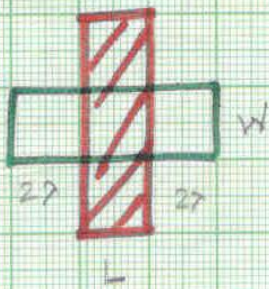
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- The size of a MOSFET depends on the reference inverter design.
- The reference inverter for nMOS logic design is the inverter with depletion mode load.
- $Z_{PD}$  = Aspect Ratio of pull-down =  $L_{PD}/W_{PD}$
- $Z_{PU}$  = Aspect Ratio of pull-up =  $L_{PU}/W_{PU}$
- The ratio of aspect ratio of Pull-up and Pull-down is known as Inverter Ratio i.e.  $R_{inv} = Z_{PU} / Z_{PD}$
- When we draw a stick diagram, inverter ratio should be mentioned for that gate.
- When a we draw a stick diagram, aspect ratio should be mentioned for all the MOSFETS.

# Inverter Ratio for NMOS Gates :

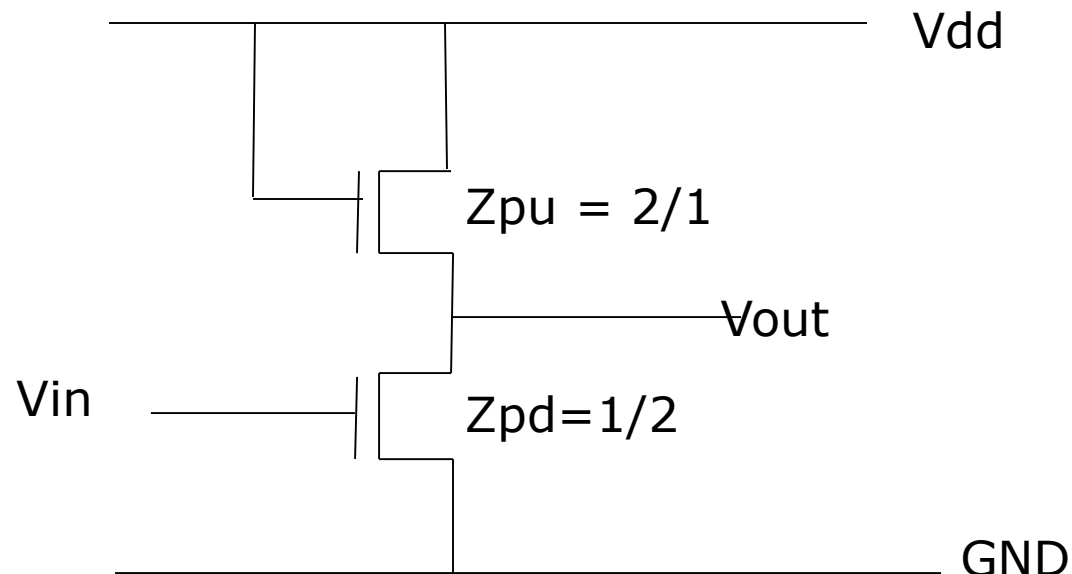
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Gates	$R_{inv}$	$Z_{PU}$	$Z_{PD}$
Inverter	4	2:1	1:2
		4:1	1:1
	8	8:1	1:1
		4:1	1:2
		2:1	1:4
NAND (2 I/P)	4	4:1	1:2 (Each)
		2:1	1:4 (Each)
NOR (2 I/P)	4	2:1	1:2 (Each)
		4:1	1:1 (Each)



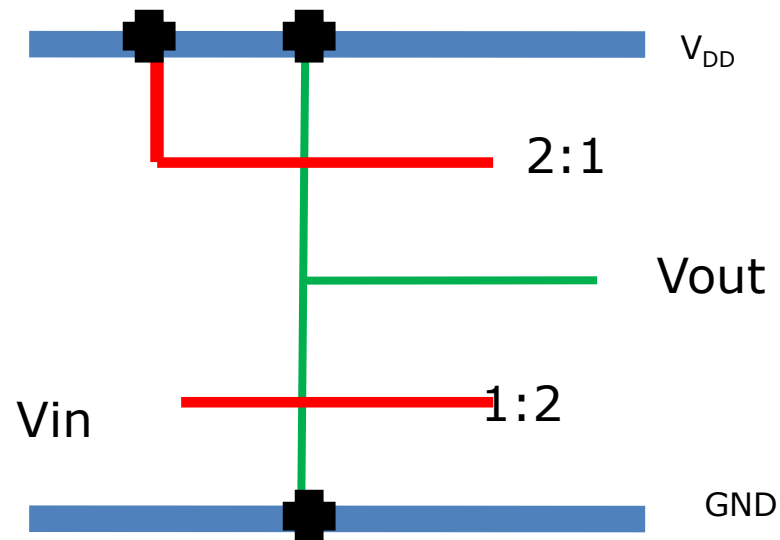
# NMOS Inverter: Enhancement load

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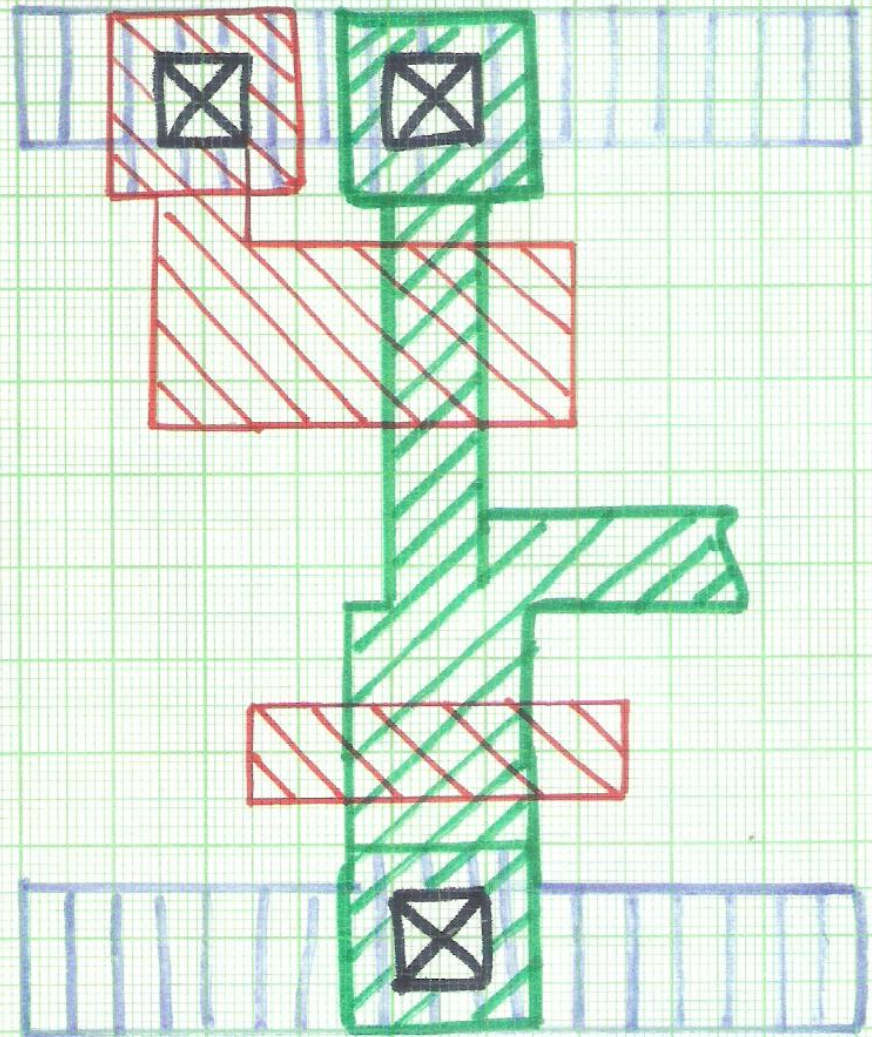
# NMOS Inverter: Enhancement load (Stick diagram)

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## NMOS INVERTER- Enhancement load

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# Interlayer Contacts :

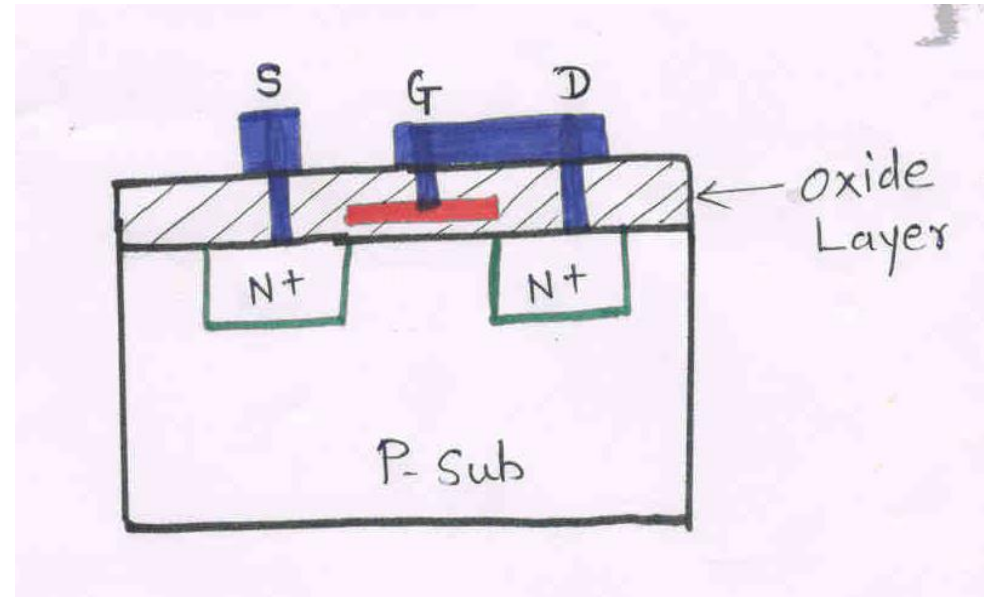
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- ❑ Interconnection between poly and diffusion is done by contacts.
- ❑ Metal contact
- ❑ Butting contact
- ❑ Buried contact

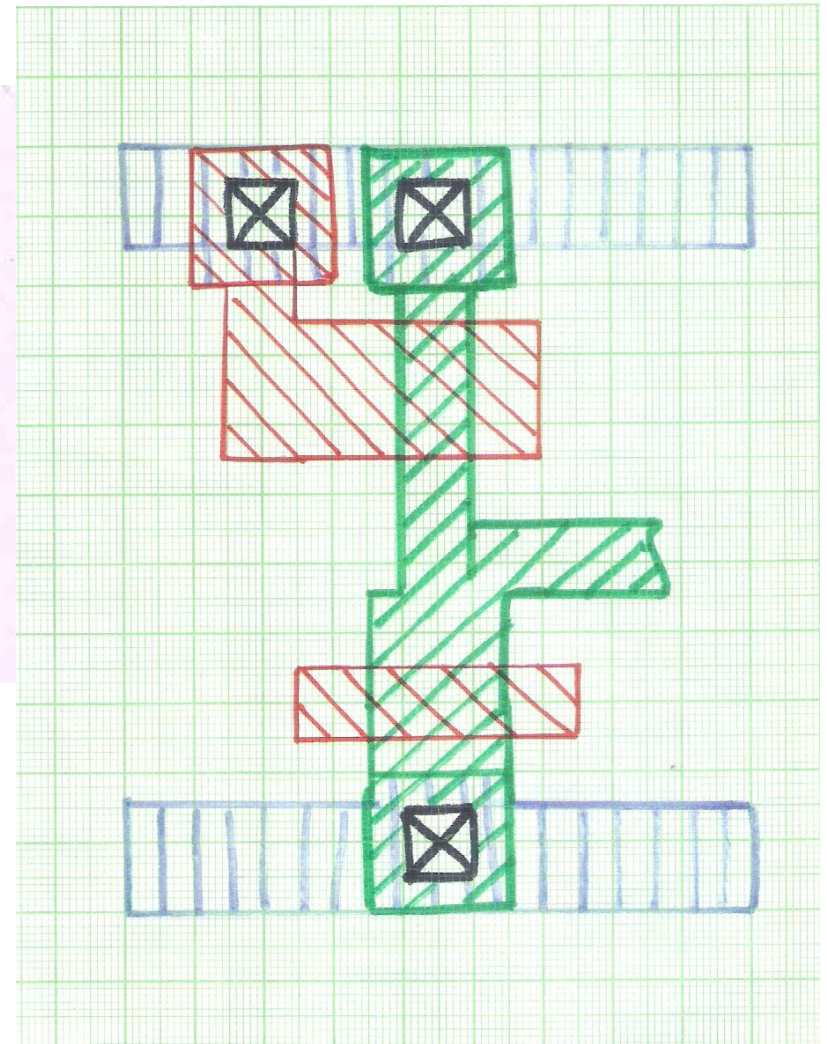
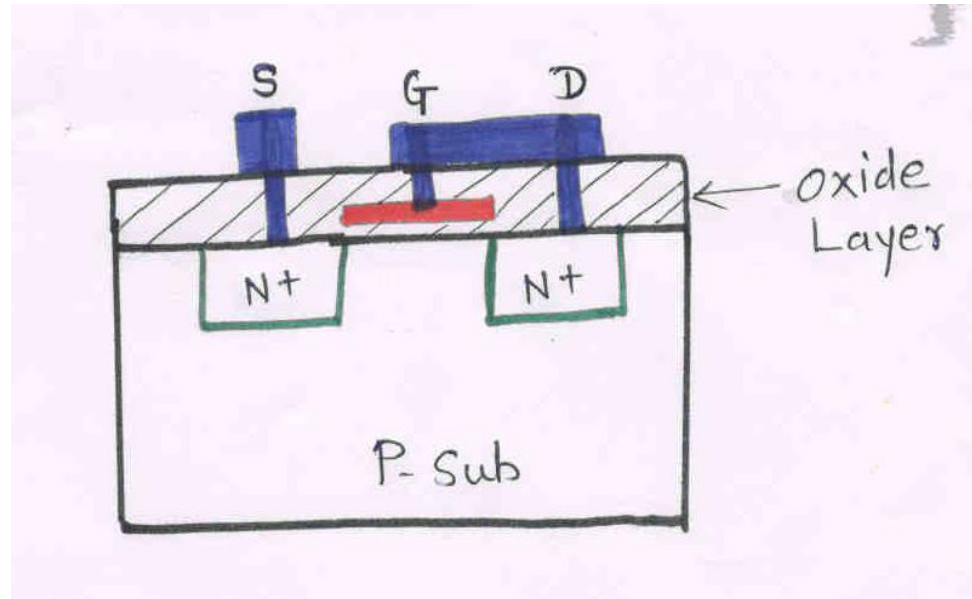
# Metal contact :

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- ❑ Contact cut of  $2\lambda * 2\lambda$  in oxide layer above poly and diffusion
- ❑ Metal used for interconnection
- ❑ Individual contact size becomes  $4\lambda * 4\lambda$



## Metal contact :

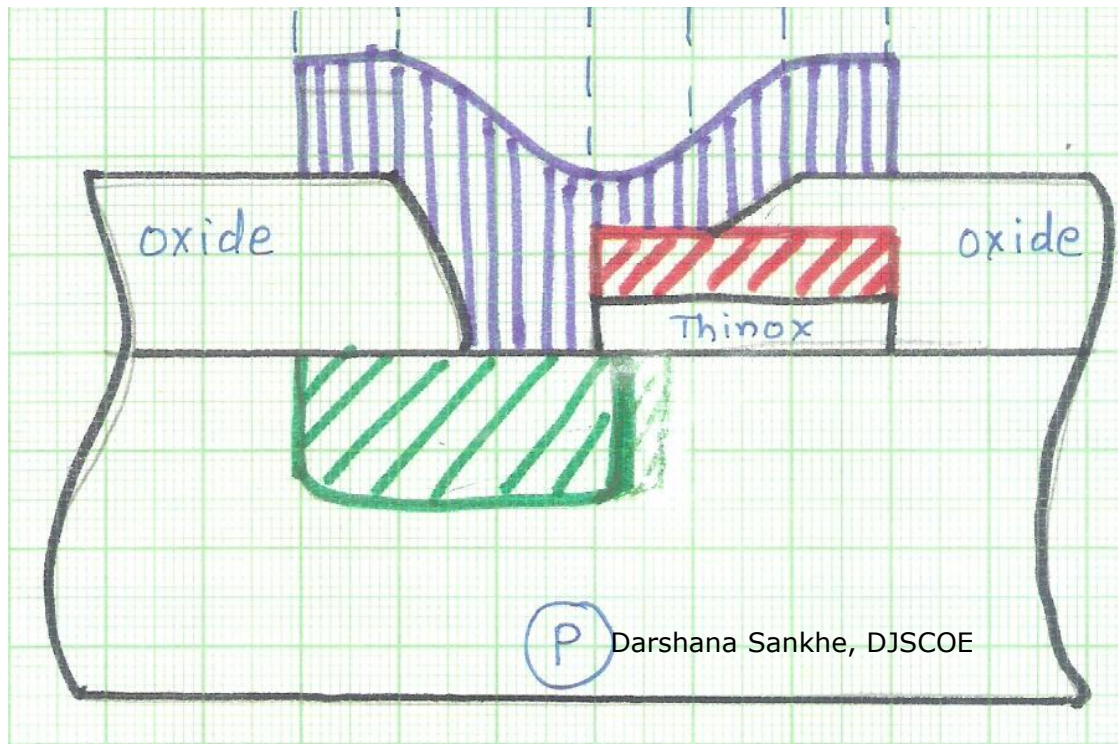
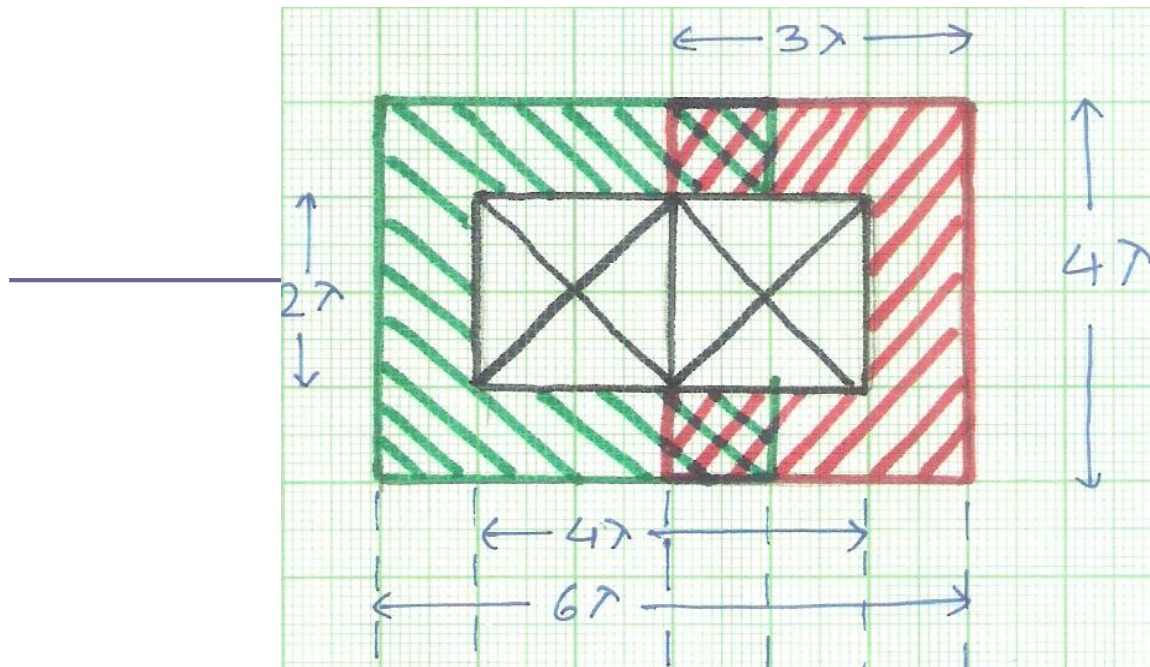


# Butting Contact

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- The Poly(gate) and diffusion(Drain) of NMOS device can be connected by a **butting contact**.
- **Two contact cuts are adjacent to each other**
- **Therefore effective contact area is less**
- Here metal makes contact to both the diffusion forming the drain of the transistor and to the polySi forming this device's gate.

## Butting Contact :



# Butting Contact

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- Metallization is required only over the butting contact holes which are  $2\lambda \times 4\lambda$  in size
- A border of width  $\lambda$  around all four sides is added to allow for mis-registration and to ensure proper contact.
- This brings the metallization size to  $4\lambda \times 6\lambda$

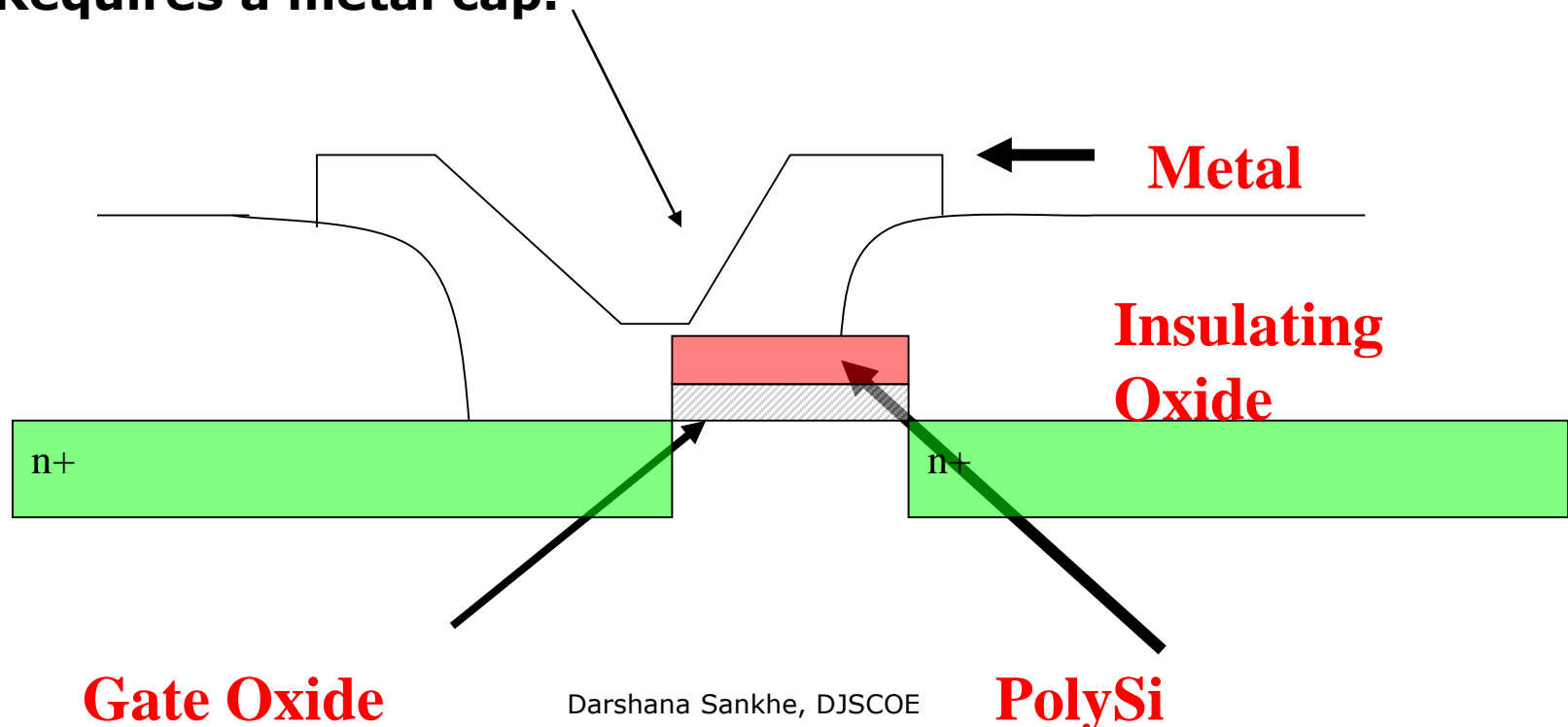
## **Advantage:**

- No buried contact mask required and avoids associated processing.

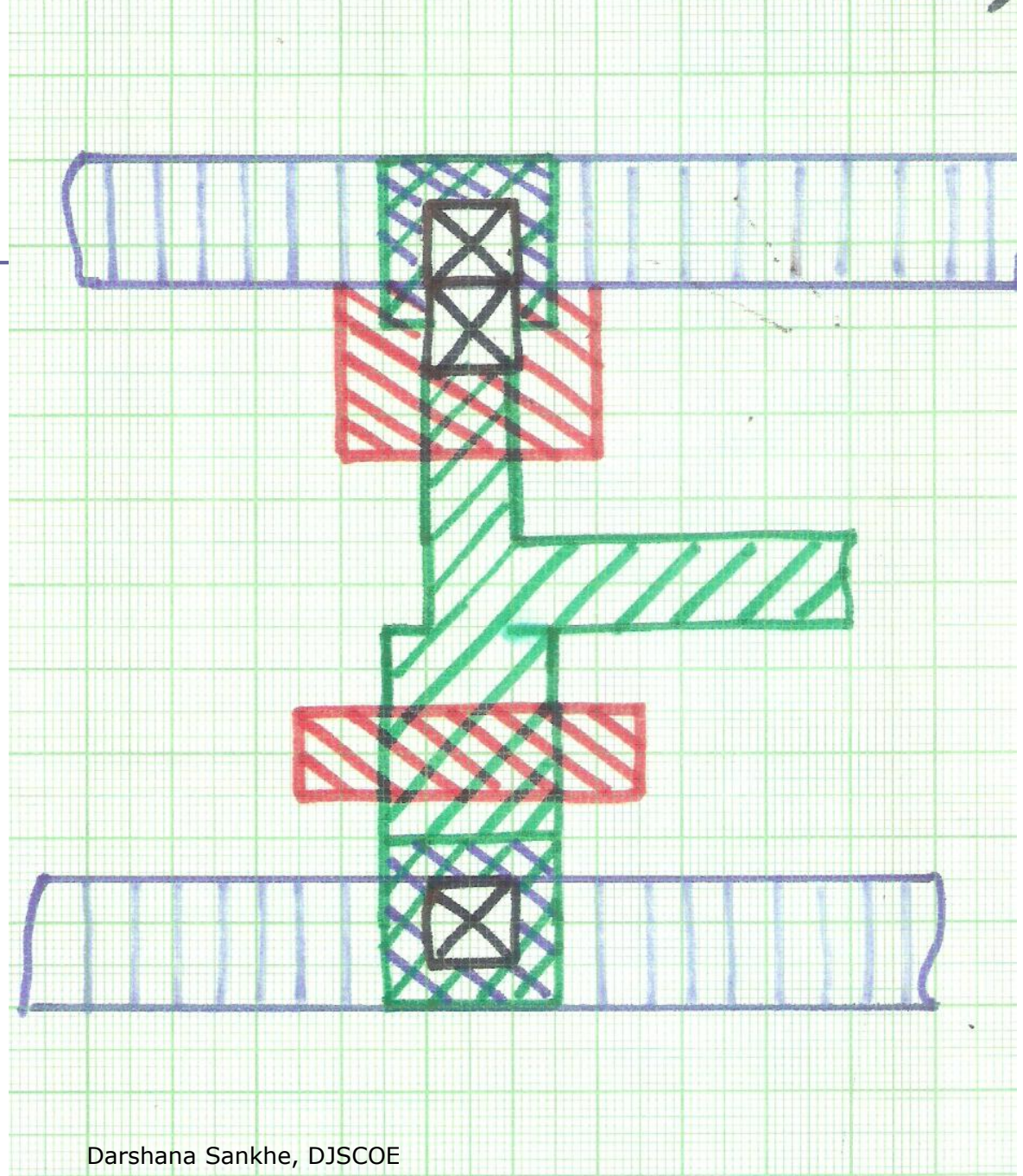
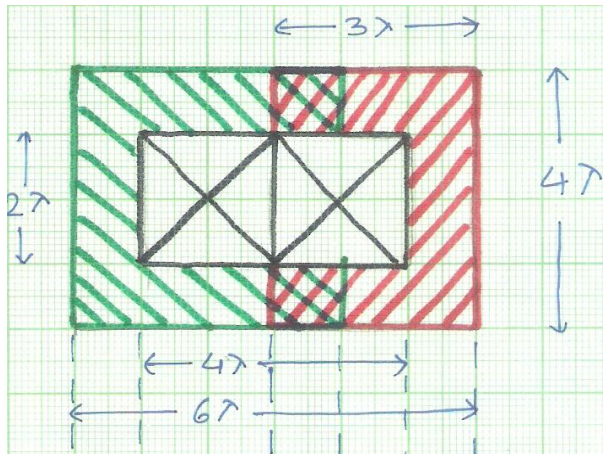
# Butting Contact

## Disadvantages:

- Metal descending the hole has a tendency to fracture at the polySi corner, causing an open circuit.
- Requires a metal cap.

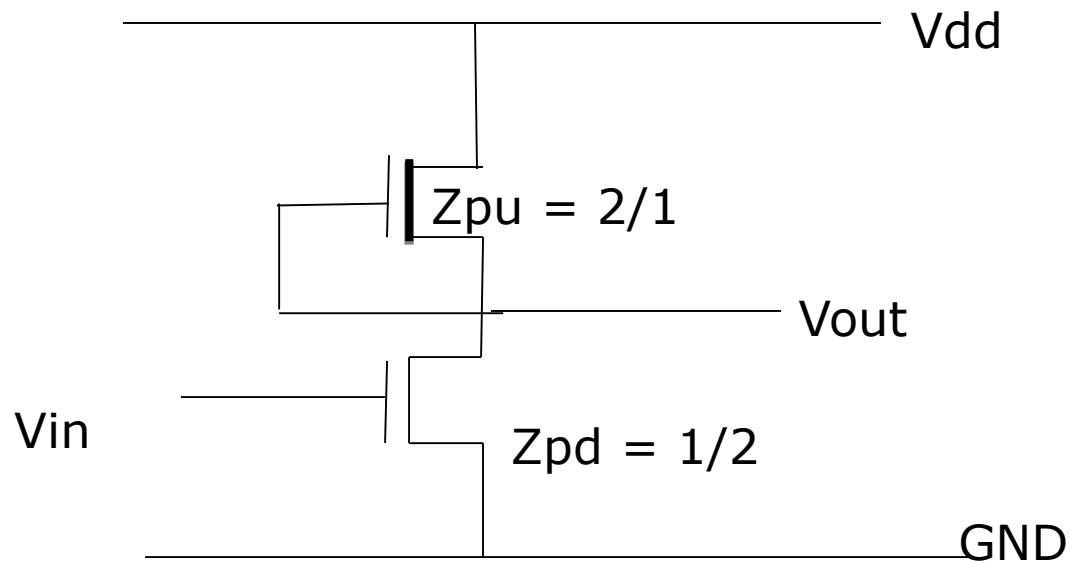


## NMOS INVERTER- Enhancement load



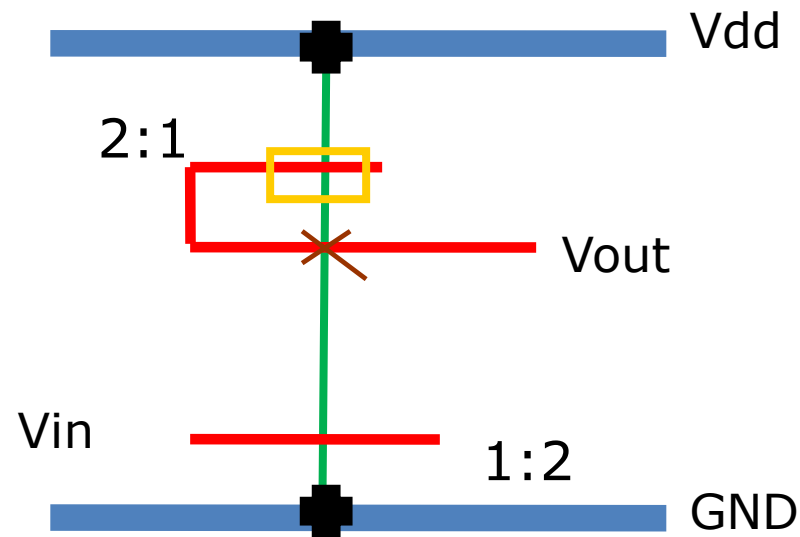
# NMOS Inverter: Depletion load

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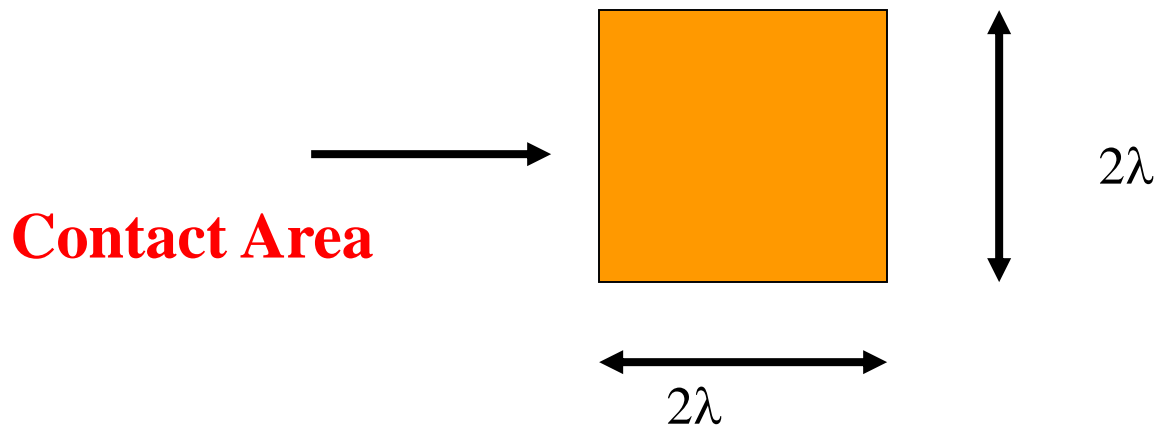
# NMOS Inverter: Depletion load (Stick Diagram)

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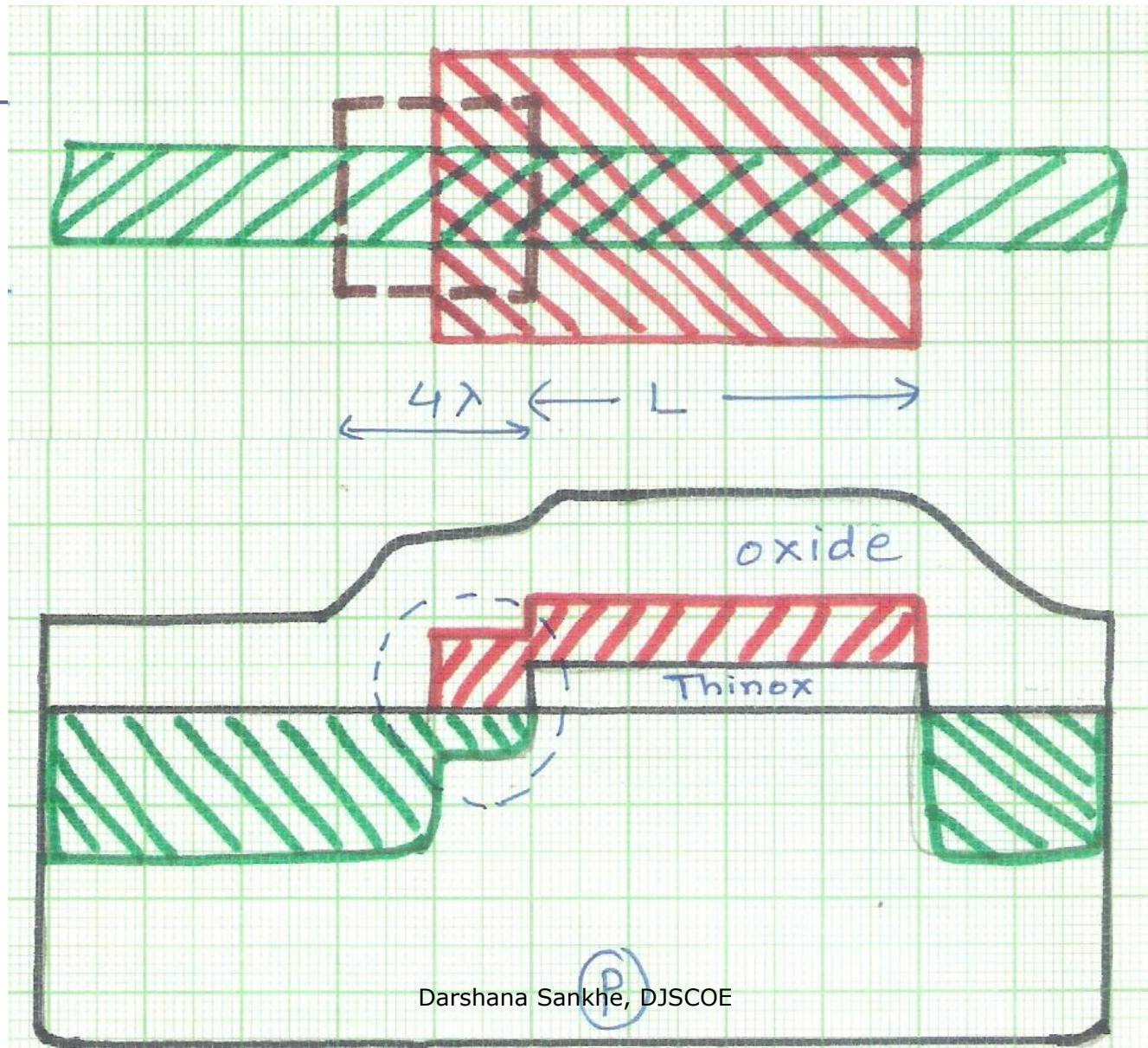
# Buried Contact

- The buried contact window defines the area where oxide is to be removed so that polySi connects directly to diffusion.
- Contact Area must be a min. of  $2\lambda * 2\lambda$  to ensure adequate contact area.

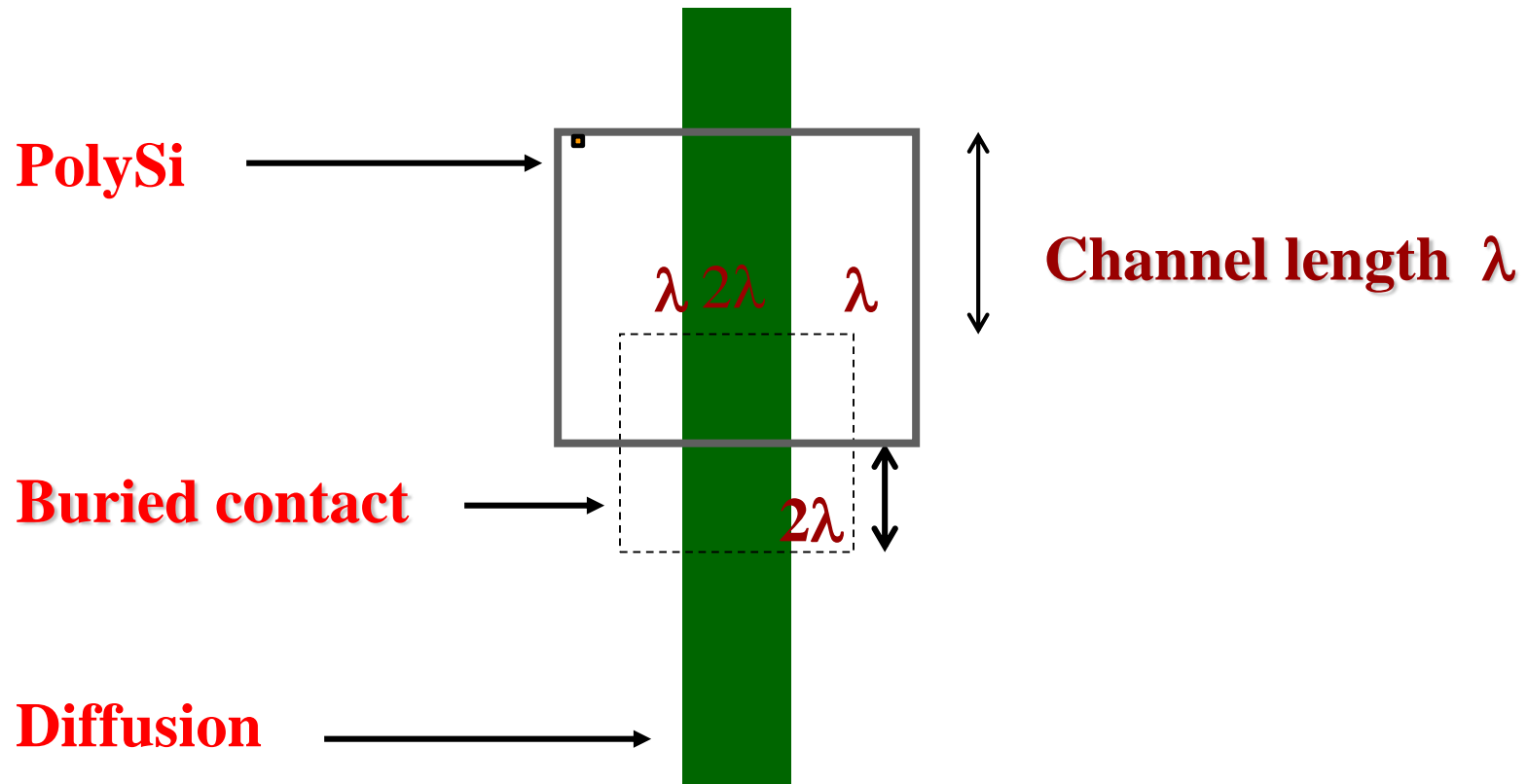


- **Advantages: No metal cap required.**
- **Disadvantage: An extra mask is required.**

# Buried contact :

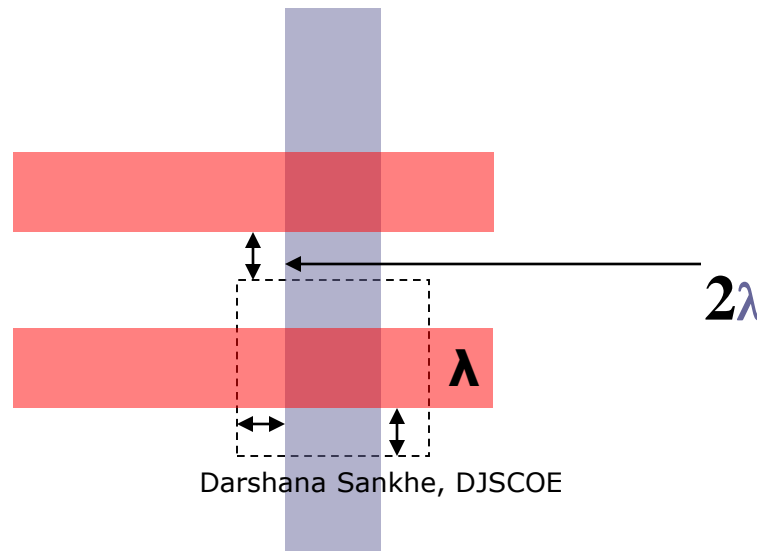


# Buried Contact



# Buried Contact

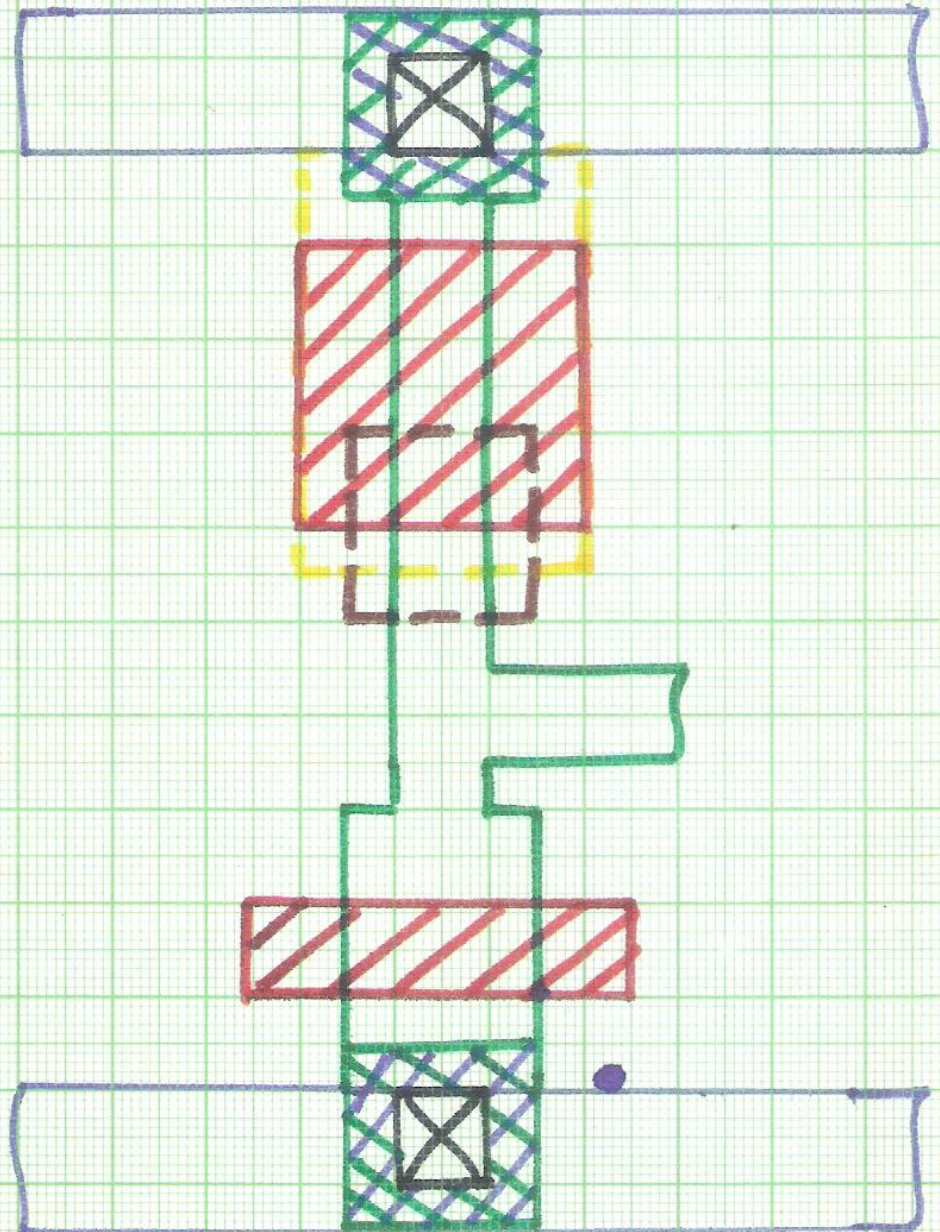
- The **buried contact window** surrounds this contact by  $\lambda$  in all directions to avoid any part of this area forming a transistor.
- Separated from its **related transistor gate** by  $2\lambda$  to prevent gate area from being reduced.



# NMOS INVERTER

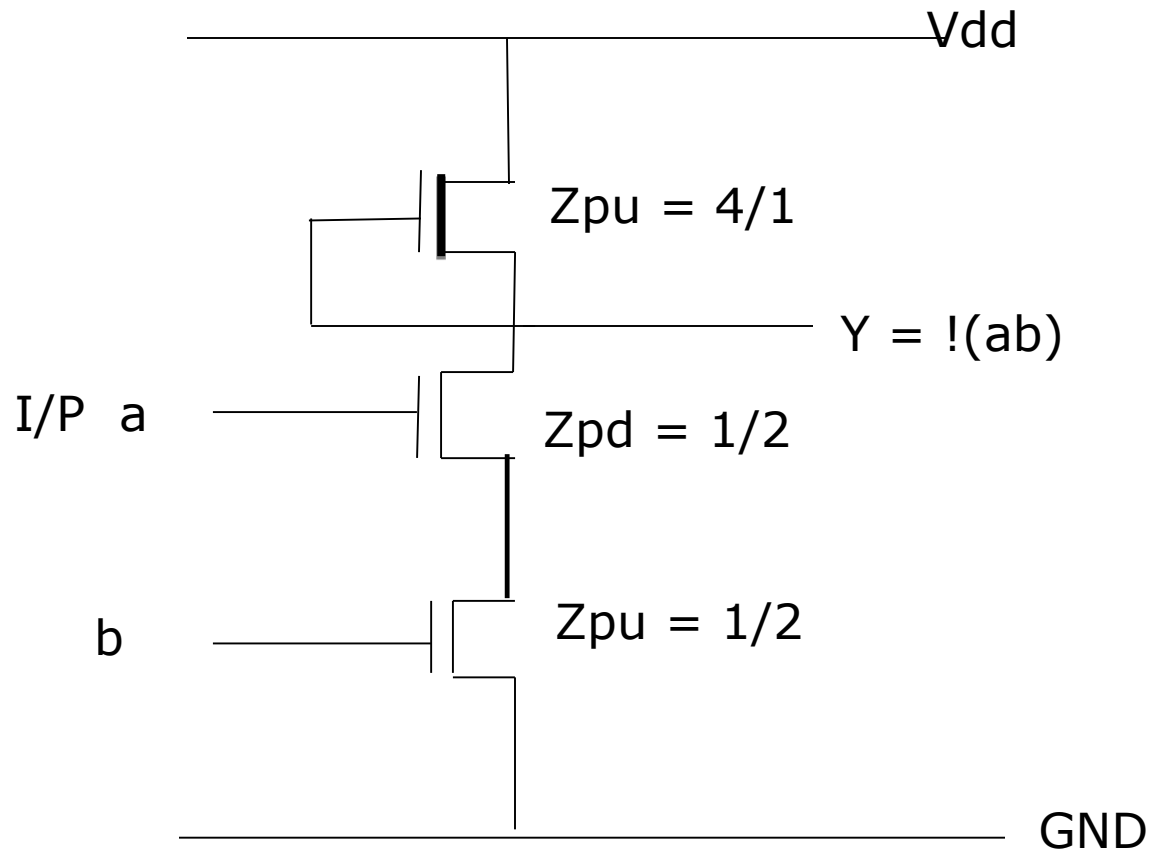
## Depletion load

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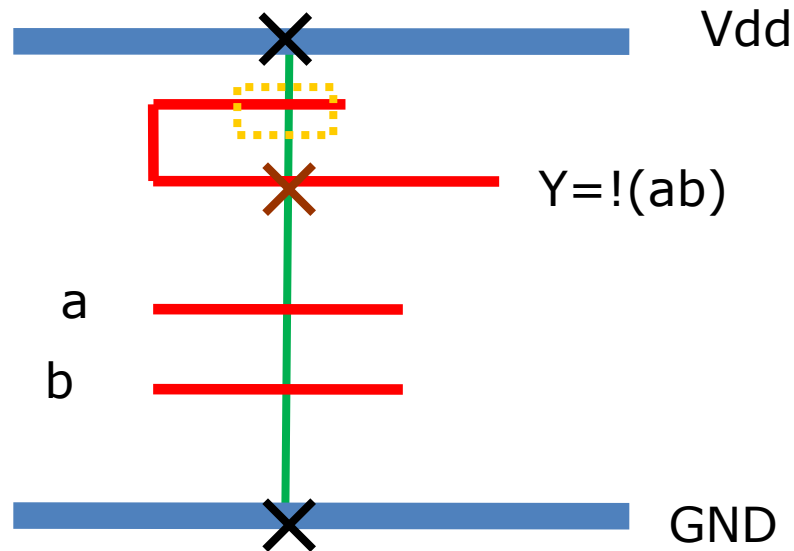
# NMOS 2 I/P NAND Gate :

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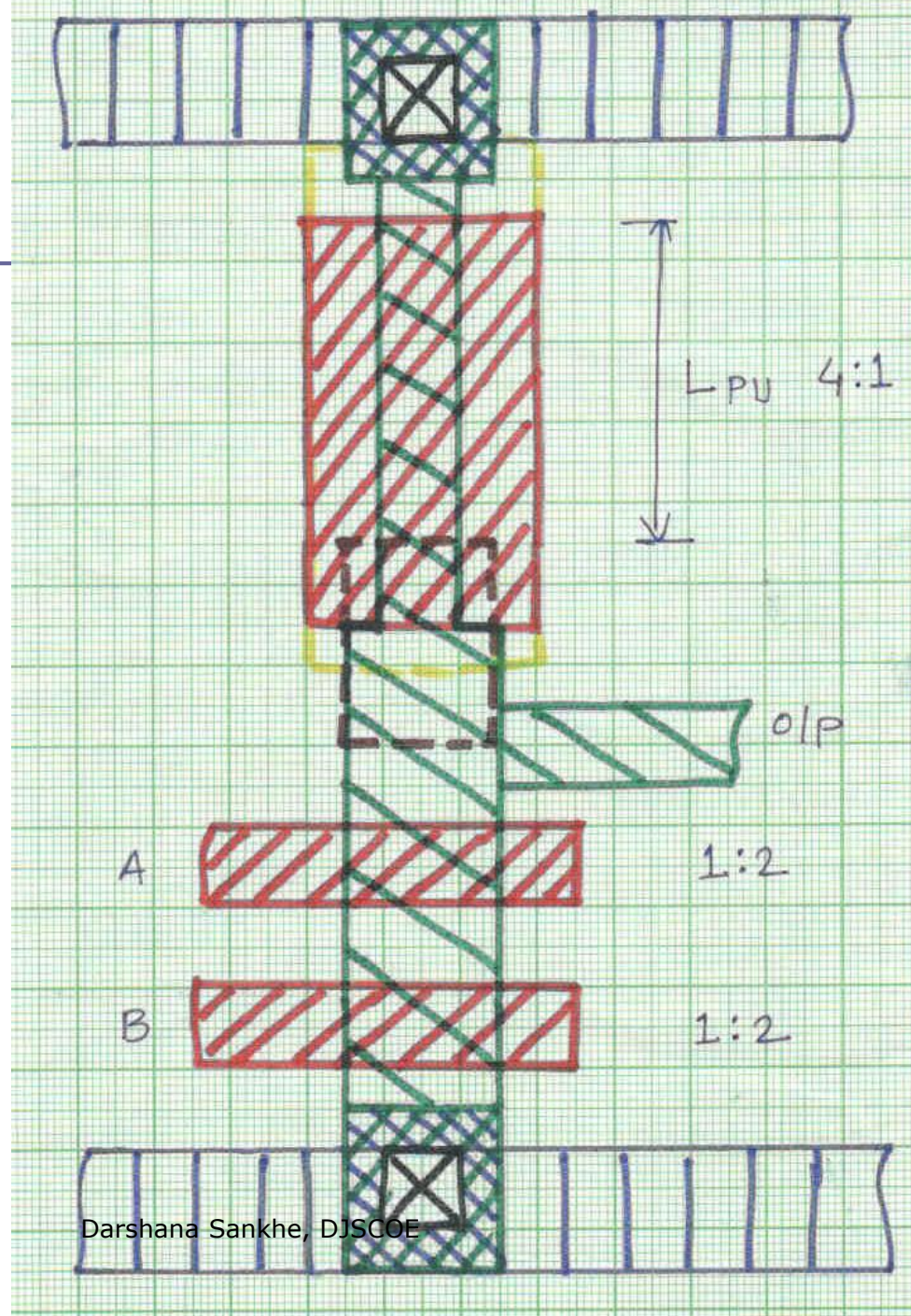


# NMOS NAND (Stick Diagram) :

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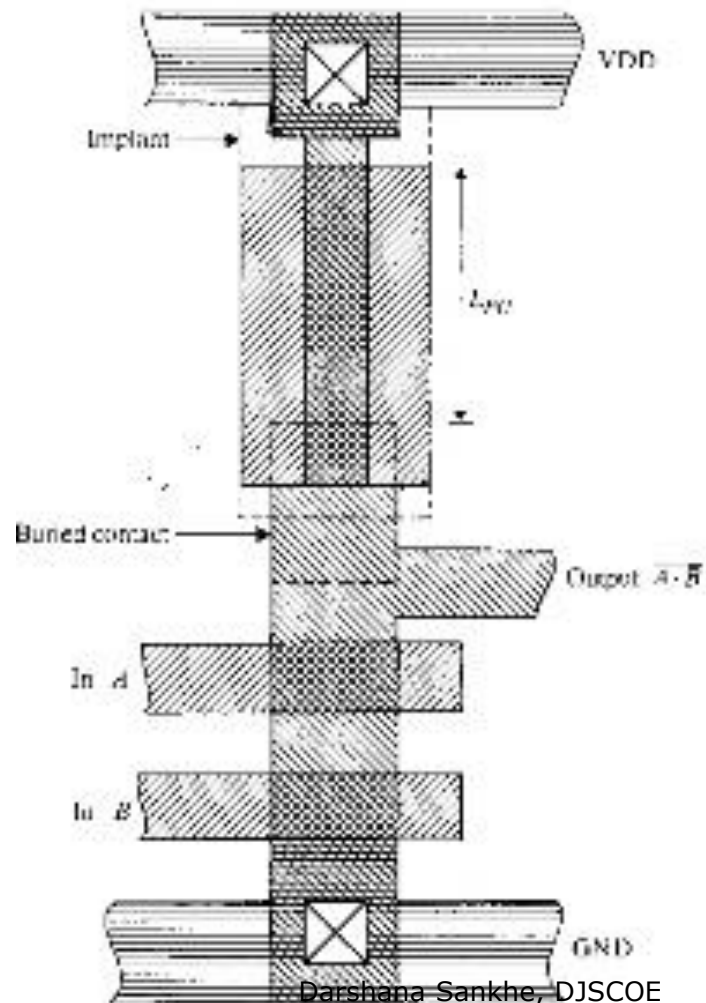


# NMOS NAND



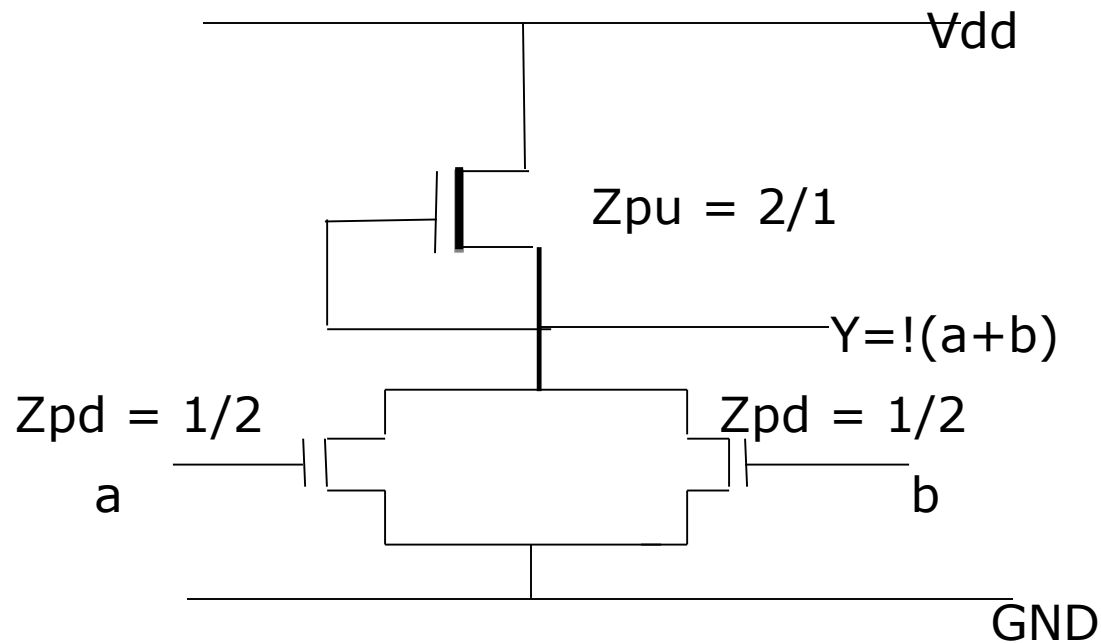
# NMOS NAND

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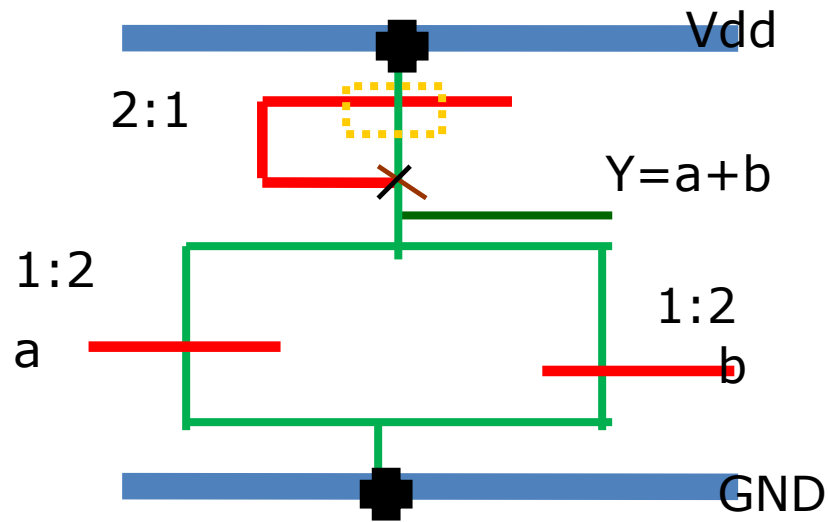


# NMOS 2 I/P NOR Gate :

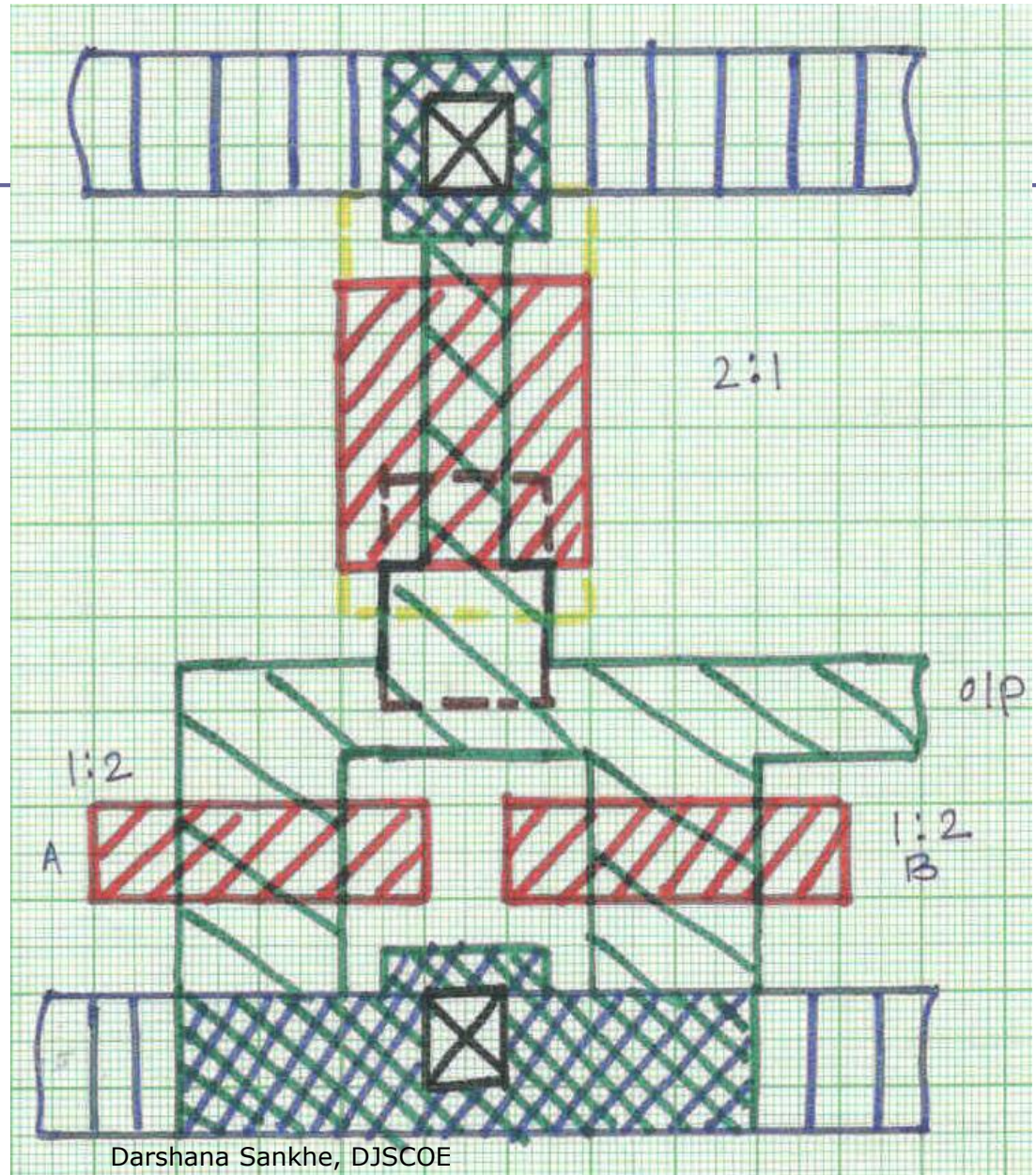
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# NMOS NOR (Stick Diagram)



# NMOS NOR



# NMOS NAND and NOR :

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## NMOS NAND

- ❑ Two nmos in series.
- ❑ Gate delay and area increases with increase in no of inputs.
- ❑ Length also increases with increase in no of input.
- ❑ NMOS NAND is slower for same no of inputs and power dissipation.

## NMOS NOR

- ❑ Two nmos in parallel.
- ❑ NOR works quite well for any no of inputs.
- ❑ Width is proportional to number of inputs.
- ❑ NMOS NOR is faster for same no of inputs and power dissipation.

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# **Thank you**